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N-Channel 650V (D-S) 175 °C MOSFET

PRODUCT SUMMARY					
V _{DS} (V) at T _J max.	700				
R _{DS(on)} max. at 25 °C (Ω)	$V_{GS} = 10 \text{ V}$	1.3			
Q _g max. (nC)	48				
Q _{gs} (nC)	6				
Q _{gd} (nC)	11				
Configuration	Single				

FEATURES





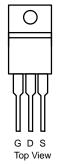
• Low Input Capacitance (Ciss)

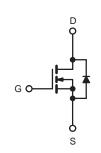
- Reduced Switching and Conduction Losses
- Ultra Low Gate Charge (Q_q)
- Avalanche Energy Rated (UIS)

APPLICATIONS

- Server and Telecom Power Supplies
- Switch Mode Power Supplies (SMPS)
- Power Factor Correction Power Supplies (PFC)
- Lighting
 - High-Intensity Discharge (HID)
 - Fluorescent Ballast Lighting

TO-220AB





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	650		
Gate-Source Voltage			V _{GS}	± 20	V	
Gate-Source Voltage AC (f > 1 Hz)				30		
Continuous Drain Current (T _J = 150 °C)	V _{GS} at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	I _D	7	А	
	VGS at 10 V	T _C = 100 °C		5		
Pulsed Drain Current ^a			I _{DM}	18		
Linear Derating Factor				0.63	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	56	mJ	
Maximum Power Dissipation			P_{D}	78	W	
Operating Junction and Storage Temperature Range			T_J, T_{stg}	- 55 to + 150	°C	
Drain-Source Voltage Slope	T _J = 125 °C dV/dt		37	V/ns		
Reverse Diode dV/dt ^d			uv/ut			27
Soldering Recommendations (Peak Temperature) ^c for 10 s			300	°C		

- a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD}=50$ V, starting $T_J=25$ °C, L=28.2 mH, $R_g=25$ Ω , $I_{AS}=2$ A.
- c. 1.6 mm from case.
- d. $I_{SD} \le I_D$, dI/dt = 100 A/ μ s, starting $T_J = 25$ °C.



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THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	62	°C/W		
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.6	G/ VV		

SPECIFICATIONS (T _J = 25 °C, u			T COMPITIONS	BAINI	TVD	MAN	11411-
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		_		,	1	1	
Drain-Source Breakdown Voltage	V_{DS}	V _{GS} = 0 V, I _D = 250 μA		650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, $I_D = 1 \text{ mA}$	-	0.73	-	V/°C
Gate-Source Threshold Voltage (N)	$V_{GS(th)}$	V _{DS} :	$= V_{GS}, I_D = 250 \mu A$	2	-	4	V
Gate-Source Leakage	I_{GSS}		$V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 650 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	1 10	μA
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 0.20 \text{ V}$	I _D = 3 A	-	0.9	1.3	Ω
Forward Transconductance	9 _{fs}		$S_1 = 30 \text{ V}, I_D = 3 \text{ A}$	-	2	-	S
Dynamic							
Input Capacitance	C _{iss}	V 0V		-	820	-	
Output Capacitance	C _{oss}		$V_{GS} = 0 \text{ V}, $ $V_{DS} = 100 \text{ V},$		40	-	1
Reverse Transfer Capacitance	C _{rss}	f = 1 MHz ²		-	4	-	1
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V _{DS} = 0 V to 520 V, V _{GS} = 0 V		-	36	-	pF
Effective Output Capacitance, Time Related ^b	$C_{o(tr)}$			-	117	-	
Total Gate Charge	Qg		1		24	48	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 3 \text{ A}, V_{DS} = 520 \text{ V}$		-	6	-	nC
Gate-Drain Charge	Q _{gd}	1			11	-	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 520 \text{ V, } I_{D} = 3 \text{ A,}$ $V_{GS} = 10 \text{ V, } R_{g} = 9.1 \Omega$		-	14	28	ns
Rise Time	t _r			-	12	24	
Turn-Off Delay Time	$t_{d(off)}$			-	30	60	
Fall Time	t _f			-	20	40	
Gate Input Resistance	R_g	f = 1 MHz, open drain		-	1.4	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	
Pulsed Diode Forward Current	I _{SM}			-	-	18	A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 3 A, V _{GS} = 0 V		-	-	1.3	V
Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = I_S = 3 \text{ A},$ $dI/dt = 100 \text{ A/µs}, V_R = 25 \text{ V}$		-	237	-	ns
Reverse Recovery Charge	Q _{rr}			-	2.2	-	μC
Reverse Recovery Current	I _{RRM}			-	16	_	Α

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

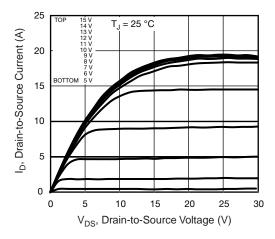


Fig. 1 - Typical Output Characteristics

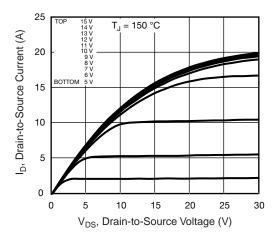


Fig. 2 - Typical Output Characteristics

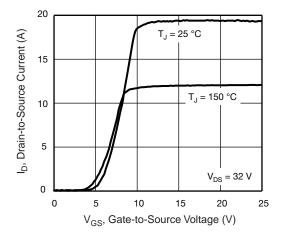


Fig. 3 - Typical Transfer Characteristics

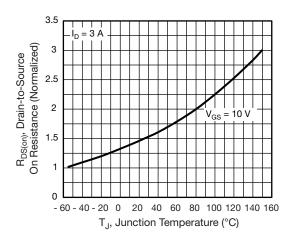


Fig. 4 - Normalized On-Resistance vs. Temperature

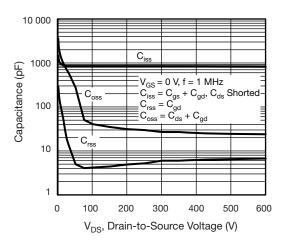


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

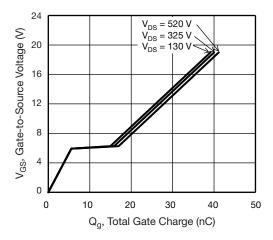


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



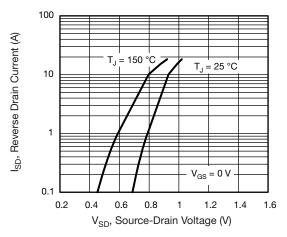


Fig. 7 - Typical Source-Drain Diode Forward Voltage

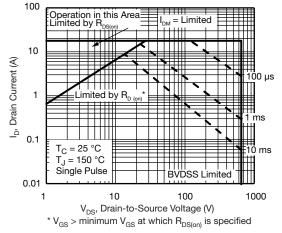


Fig. 8 - Maximum Safe Operating Area

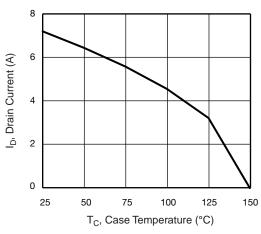


Fig. 9 - Maximum Drain Current vs. Case Temperature

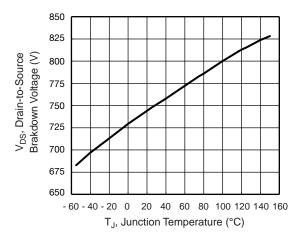


Fig. 10 - Temperature vs. Drain-to-Source Voltage

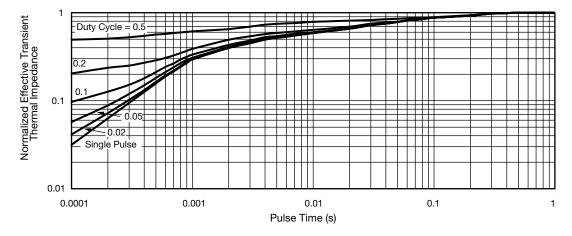


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



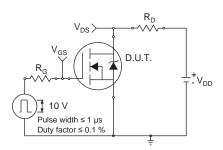


Fig. 12 - Switching Time Test Circuit

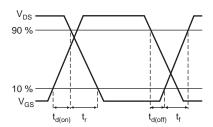


Fig. 13 - Switching Time Waveforms

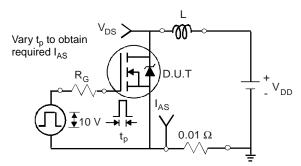


Fig. 14 - Unclamped Inductive Test Circuit

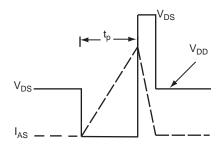


Fig. 15 - Unclamped Inductive Waveforms

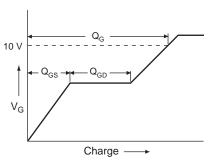


Fig. 16 - Basic Gate Charge Waveform

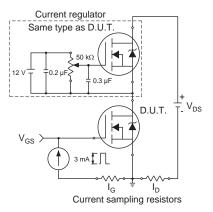
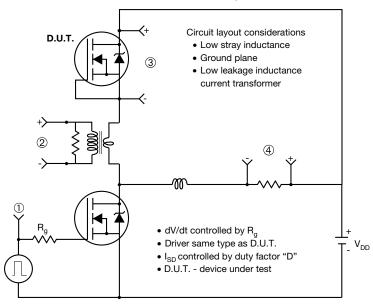


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



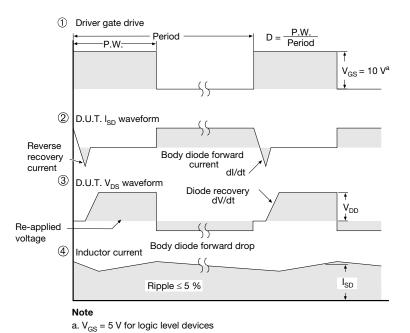
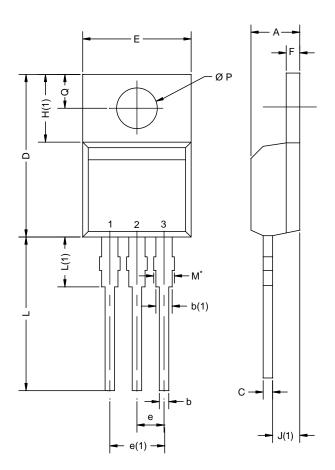


Fig. 18 - For N-Channel



TO-220AB



	MILLIM	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

 $^{^{*}}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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